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April 1st, 2010 Renesas Electronics Corporation

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 $4 \text{ M SRAM} (256\text{-kword} \times 16\text{-bit})$



ADE-203-934C (Z) Rev. 2.0 Oct. 14, 1999

Description

The Hitachi HM62W16256B Series is 4-Mbit static RAM organized 262,144-word × 16-bit. HM62W16256B Series has realized higher density, higher performance and low power consumption by employing Hi-CMOS process technology. It offers low power standby power dissipation; therefore, it is suitable for battery backup systems. It is packaged in standard 44-pin plastic TSOPII.

Features

Single 3.3 V supply: 3.3 V ± 0.3 V
 Fast access time: 55 ns/70 ns (max)

Power dissipation:

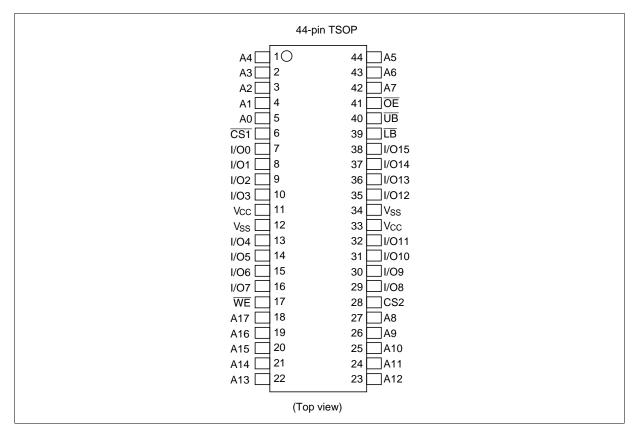
— Active: 9.9 mW (typ)— Standby: 3.3 μW (typ)

- Completely static memory.
 - No clock or timing strobe required
- Equal access and cycle times
- Common data input and output.
 - Three state output
- Battery backup operation.
 - 2 chip selection for battery backup

Ordering Information

Type No.	Access time	Package
HM62W16256BLTT-5 HM62W16256BLTT-7	55 ns 70 ns	400-mil 44-pin plastic TSOPII (normal-bend type) (TTP-44DB)
HM62W16256BLTT-5SL HM62W16256BLTT-7SL	55 ns 70 ns	

Pin Arrangement

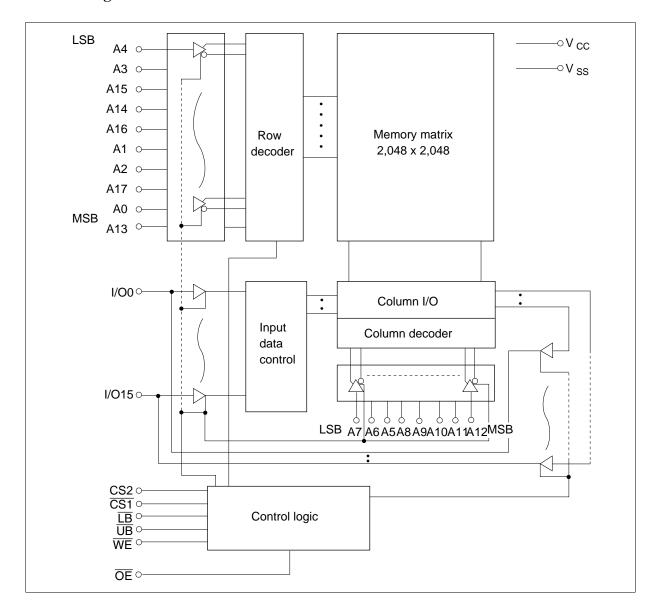


Pin Description

Pin name	Function
A0 to A17	Address input
I/O0 to I/O15	Data input/output
CS1	Chip select 1
CS2	Chip select 2
WE	Write enable
ŌE	Output enable
LB	Lower byte select
ŪB	Upper byte select
V _{cc}	Power supply
V_{ss}	Ground

3

Block Diagram



Operation Table

CS1	CS2	WE	OE	UB	LB	I/O0 to I/O7	I/O8 to I/O15	Operation
Н	×	×	×	×	×	High-Z	High-Z	Standby
×	L	×	×	×	×	High-Z	High-Z	Standby
×	×	×	×	Н	Н	High-Z	High-Z	Standby
L	Н	Н	L	L	L	Dout	Dout	Read
L	Н	Н	L	Н	L	Dout	High-Z	Lower byte read
L	Н	Н	L	L	Н	High-Z	Dout	Upper byte read
L	Н	L	×	L	L	Din	Din	write
L	Н	L	×	Н	L	Din	High-Z	Lower byte write
L	Н	L	×	L	Н	High-Z	Din	Upper byte write
L	Н	Н	Н	×	×	High-Z	High-Z	Output disable

Note: $H: V_{IH}, L: V_{IL}, \times: V_{IH} \text{ or } V_{IL}$

Absolute Maximum Ratings

Parameter	Symbol	Value	Unit
Power supply voltage relative to V _{SS}	V _{cc}	-0.5 to + 4.6	V
Terminal voltage on any pin relative to V _{ss}	V _T	-0.5^{*1} to $V_{CC} + 0.3^{*2}$	V
Power dissipation	P _T	1.0	W
Storage temperature range	Tstg	-55 to +125	°C
Storage temperature range under bias	Tbias	-10 to +85	°C

Notes: 1. V_T min: -3.0 V for pulse half-width ≤ 30 ns.

2. Maximum voltage is +4.6 V.

DC Operating Conditions

Parameter	Symbol	Min	Тур	Max	Unit	Note
Supply voltage	V _{cc}	3.0	3.3	3.6	V	
	V _{ss}	0	0	0	V	
Input high voltage	V_{IH}	2.0	_	$V_{cc} + 0.3$	V	
Input low voltage	V_{IL}	-0.3	_	0.8	V	1
Ambient temperature range	Та	0	_	70	°C	

Note: 1. V_{IL} min: -3.0 V for pulse half-width ≤ 30 ns.

DC Characteristics

Parameter		Symbol	Min	Typ* ¹	Max	Unit	Test conditions	
Input leaka	age current	I _{LI}	_	_	1	μΑ	$Vin = V_{SS}$ to V_{CC}	
Output lea	kage current	I _{LO}	_	_	1	μА	$\overline{\frac{\text{CS1}}{\text{OE}}} = V_{\text{IH}} \text{ or } \text{CS2} = V_{\text{IL}} \text{ or } \\ \overline{\text{OE}} = V_{\text{IH}} \text{ or } \overline{\text{WE}} = V_{\text{IL}}, \text{ or } \\ \overline{\text{LB}} = \overline{\text{UB}} = V_{\text{H}} \\ V_{\text{I/O}} = V_{\text{SS}} \text{ to } V_{\text{CC}}$	
Operating	current	I _{cc}	_	_	20	mA	$\overline{\text{CS1}} = \text{V}_{\text{IL}}, \text{CS2} = \text{V}_{\text{IH}},$ Others = $\text{V}_{\text{IH}}/\text{V}_{\text{IL}}, \text{I}_{\text{I/O}} = 0 \text{ mA}$	
Average operating current	HM62W16256B-5	I _{CC1}	_	_	80	mA	Min. cycle, duty = 100%, $I_{I/O} = 0$ mA, $\overline{CS1} = V_{IL}$, CS2 = V_{IH} , Others = V_{IH}/V_{IL}	
	HM62W16256B-7	I _{CC1}	_	_	70	mA		
		I _{CC2}	_	3	15	mA	$\begin{split} &\text{Cycle time} = 1 \; \mu\text{s, duty} = 100\%, \\ &\text{I}_{\text{I/O}} = 0 \; \text{mA}, \; \overline{\text{CS1}} \leq 0.2 \; \text{V}, \\ &\text{CS2} \geq \text{V}_{\text{CC}} - 0.2 \; \text{V} \\ &\text{V}_{\text{IH}} \geq \text{V}_{\text{CC}} - 0.2 \; \text{V}, \; \text{V}_{\text{IL}} \leq 0.2 \; \text{V} \end{split}$	
Standby c	urrent	I_{SB}	_	_	0.3	mA	$CS2 = V_{IL}$	
Standby co	urrent	*2	_	1	40	μА	0 V \leq Vin (1) 0 V \leq CS2 \leq 0.2 V or (2) $\overline{\text{CS1}} \geq$ V $_{\text{CC}} -$ 0.2 V, $\text{CS2} \geq$ V $_{\text{CC}} -$ 0.2 V	
		I _{SB1} *3	_	1	20	μΑ		
Output hig	h voltage	V_{OH}	2.4	_	_	V	$I_{OH} = -1 \text{ mA}$	
			$V_{cc} - 0.2$	_	_	V	$I_{OH} = -100 \mu A$	
Output low	v voltage	V_{OL}	_	_	0.4	V	I _{OL} = 2 mA	
			_	_	0.2	V	I _{OL} = 100 μA	

Notes: 1. Typical values are at $V_{CC} = 3.3 \text{ V}$, $Ta = +25^{\circ}\text{C}$ and not guaranteed.

- 2. This characteristic is guaranteed only for L-version.
- 3. This characteristic is guaranteed only for L-SL version.

Capacitance (Ta = +25°C, f = 1.0 MHz)

Parameter	Symbol	Min	Тур	Max	Unit	Test conditions	Note
Input capacitance	Cin	_	_	8	pF	Vin = 0 V	1
Input/output capacitance	$C_{I/O}$	_	_	10	pF	$V_{I/O} = 0 V$	1

Note: 1. This parameter is sampled and not 100% tested.

AC Characteristics (Ta = 0 to +70°C, V_{CC} = 3.3 V \pm 0.3 V, unless otherwise noted.)

Test Conditions

• Input pulse levels: $V_{IL} = 0.4 \text{ V}$, $V_{IH} = 2.4 \text{ V}$

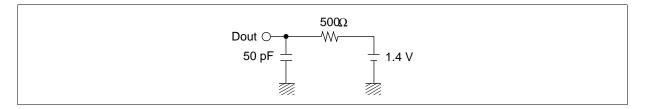
• Input rise and fall time: 5 ns

• Input timing reference levels: 1.4 V

• Output timing reference levels: 1.4 V/1.4 V (HM62W16256B-5)

: 2.0 V/0.8 V (HM62W16256B-7)

• Output load (Including scope and jig)



Read Cycle

162		

		-5		-7		_	
Parameter	Symbol	Min	Max	Min	Max	Unit	Notes
Read cycle time	t _{RC}	55	_	70	_	ns	
Address access time	t _{AA}	_	55	_	70	ns	
Chip select access time	t _{ACS1}	_	55	_	70	ns	
	t _{ACS2}	_	55	_	70	ns	
Output enable to output valid	t _{OE}	_	35	_	40	ns	
Output hold from address change	t _{oh}	10	_	10	_	ns	
TB, UB access time	t _{BA}	_	55	_	70	ns	
Chip select to output in low-Z	t _{CLZ1}	10	_	10	_	ns	2, 3
	t _{CLZ2}	10	_	10	_	ns	2, 3
LB, UB enable to low-z	t _{BLZ}	5	_	5	_	ns	2, 3
Output enable to output in low-Z	t _{OLZ}	5	_	5	_	ns	2, 3
Chip deselect to output in high-Z	t _{CHZ1}	0	20	0	25	ns	1, 2, 3
	t _{CHZ2}	0	20	0	25	ns	1, 2, 3
LB, UB disable to high-Z	t _{BHZ}	0	20	0	25	ns	1, 2, 3
Output disable to output in high-Z	t _{OHZ}	0	20	0	25	ns	1, 2, 3

Write Cycle

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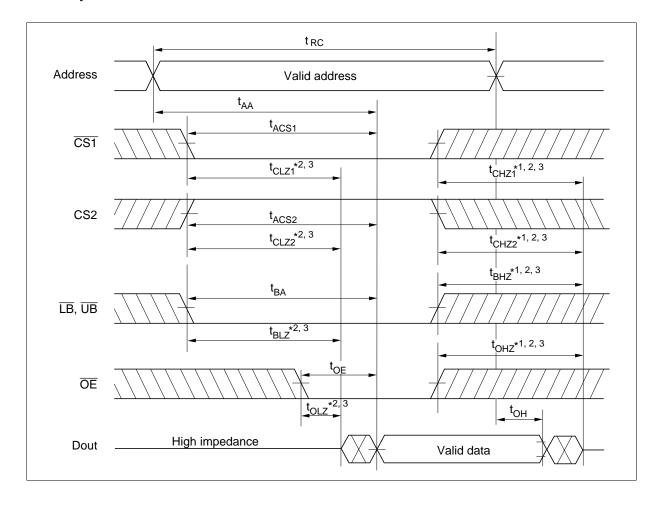
		-5		-7			
Parameter	Symbol	Min	Max	Min	Max	Unit	Notes
Write cycle time	t _{wc}	55	_	70	_	ns	
Address valid to end of write	\mathbf{t}_{AW}	50	_	60	_	ns	
Chip selection to end of write	t _{cw}	50	_	60	_	ns	5
Write pulse width	t _{WP}	40	_	50	_	ns	4
LB, UB valid to end of write	$t_{\scriptscriptstyle BW}$	50	_	55	_	ns	
Address setup time	t _{AS}	0	_	0	_	ns	6
Write recovery time	t _{WR}	0	_	0	_	ns	7
Data to write time overlap	$t_{\scriptscriptstyle DW}$	25	_	30	_	ns	
Data hold from write time	t_{DH}	0	_	0	_	ns	
Output active from end of write	t_{ow}	5	_	5	_	ns	2
Output disable to output in High-Z	t _{OHZ}	0	20	0	25	ns	1, 2
Write to output in high-Z	t _{whz}	0	20	0	25	ns	1, 2

Notes: 1. t_{CHZ} , t_{OHZ} , t_{WHZ} and t_{BHZ} are defined as the time at which the outputs achieve the open circuit conditions and are not referred to output voltage levels.

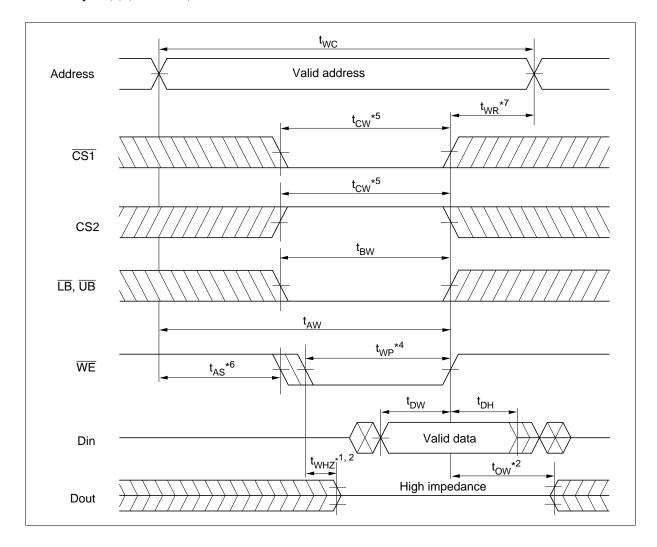
- 2. This parameter is sampled and not 100% tested.
- 3. At any given temperature and voltage condition, t_{HZ} max is less than t_{LZ} min both for a given device and from device to device.
- 4. A write occures during the overlap of a low $\overline{CS1}$, a high CS2, a low \overline{WE} and a low \overline{LB} or a low \overline{UB} . A write begins at the latest transition among $\overline{CS1}$ going low, CS2 going high, \overline{WE} going low and \overline{LB} going low or \overline{UB} going low. A write ends at the earliest transition among $\overline{CS1}$ going high, CS2 going low, \overline{WE} going high and \overline{LB} going high or \overline{UB} going high. t_{WP} is measured from the beginning of write to the end of write.
- 5. t_{cw} is measured from the later of CS1 going low or CS2 going high to the end of write.
- 6. $t_{\mbox{\scriptsize AS}}$ is measured from the address valid to the beginning of write.
- t_{WR} is measured from the earliest of CS1 or WE going high or CS2 going low to the end of write cycle.

Timing Waveform

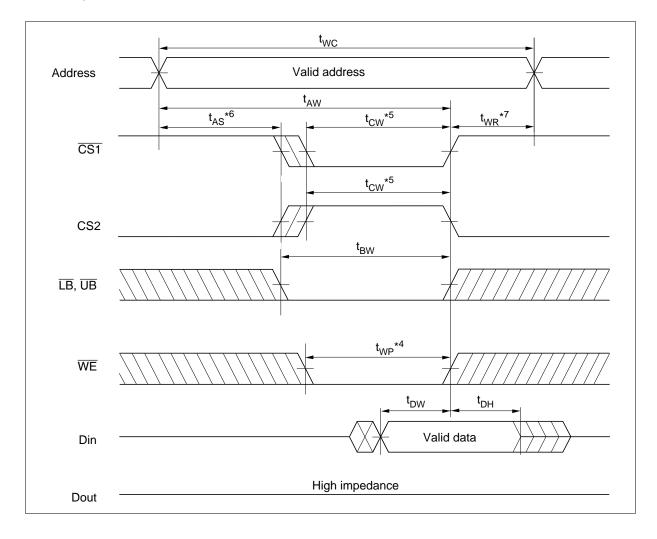
Read Cycle



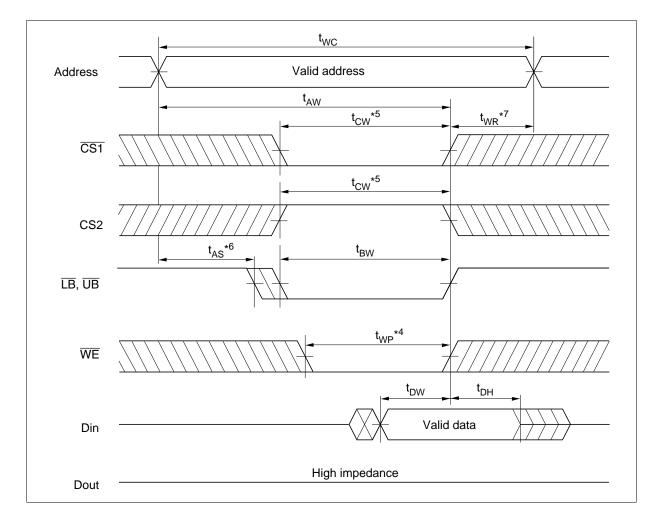
Write Cycle (1) ($\overline{\text{WE}}$ Clock)



Write Cycle (2) (\overline{CS} Clock, $\overline{OE} = V_{IH}$)



Write Cycle (3) (\overline{LB} , \overline{UB} Clock, $\overline{OE} = V_{IH}$)



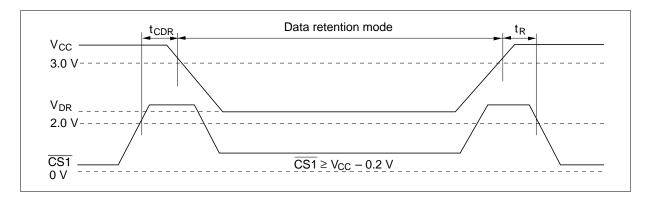
Low V_{CC} **Data Retention Characteristics** (Ta = 0 to +70°C)

Parameter	Symbol	Min	Typ* ⁴	Max	Unit	Test conditions*3
V _{cc} for data retention	V_{DR}	2.0	_	_	V	
Data retention current	I _{CCDR} * ¹	_	0.8	20	μА	$\begin{array}{c} V_{\rm CC} = 3.0 \; V, \; Vin \geq 0V \\ (1) \;\; 0 \;\; V \leq CS2 \leq 0.2 \; V \;\; or \\ (2) \;\; \frac{CS2}{2} \geq V_{\rm CC} - 0.2 \; V, \\ \hline \frac{CS1}{2} \geq V_{\rm CC} - 0.2 \; V \;\; or \\ (3) \;\; \overline{LB} = \overline{UB} \geq V_{\rm CC} - 0.2 \; V \\ \hline \frac{CS2}{2} \geq V_{\rm CC} - 0.2 \; V \\ \hline \frac{CS1}{2} \leq 0.2 \; V \end{array}$
	I _{CCDR} *2	_	0.8	10	μΑ	
Chip deselect to data retention time	t _{CDR}	0	_	_	ns	See retention waveform
Operation recovery time	t _R	t _{RC} *5	_	_	ns	

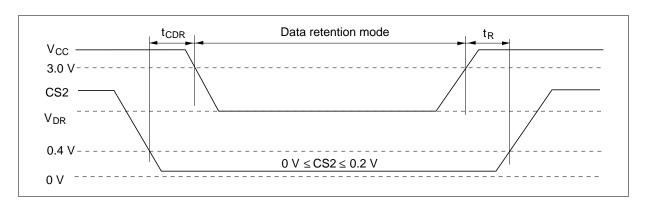
Notes: 1. This characteristic is guaranteed only for L-version, 10 μ A max. at Ta = 0 to +40°C.

- 2. This characteristic is guaranteed only for L-SL version, 5 μ A max. at Ta = 0 to +40°C.
- 3. CS2 controls address buffer, \overline{WE} buffer, $\overline{CS1}$ buffer, \overline{OE} buffer, \overline{LB} , \overline{UB} buffer and Din buffer. If CS2 controls data retention mode, Vin levels (address, \overline{WE} , \overline{OE} , $\overline{CS1}$, \overline{LB} , \overline{UB} , I/O) can be in the high impedance state. If $\overline{CS1}$ controls data retention mode, CS2 must be CS2 \geq V_{CC} 0.2 V or 0 V \leq CS2 \leq 0.2 V. The other input levels (address, \overline{WE} , \overline{OE} , \overline{LB} , \overline{UB} , I/O) can be in the high impedance state.
- 4. Typical values are at V_{cc} = 3.0 V, Ta = +25 °C and not guaranteed.
- 5. t_{RC} = read cycle time.

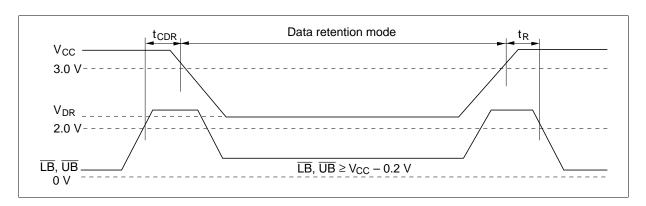
Low V_{CC} Data Retention Timing Waveform (1) ($\overline{CS1}$ Controlled)



Low V_{CC} Data Retention Timing Waveform (2) (CS2 Controlled)

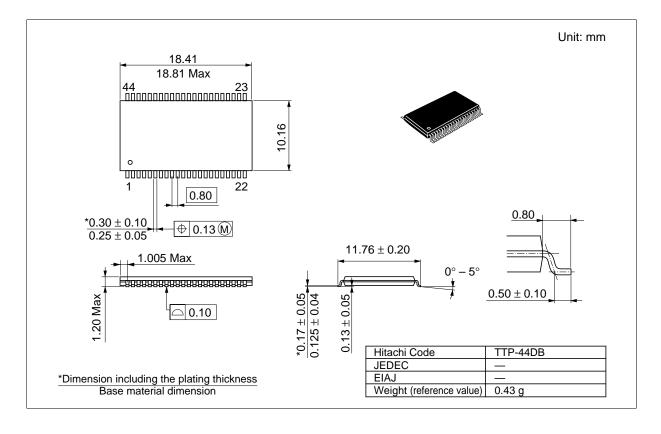


Low V_{CC} Data Retention Timing Waveform (3) (\overline{LB} , \overline{UB} Controlled)



Package Dimensions

HM62W16256BLTT Series (TTP-44DB)



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